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SERIAL NUMBER 09/891,511	FILING DATE 08/27/2001 RULE	CLASS 438	GROUP ART UNIT 2812	ATTORNEY DOCKET NO. 010319
APPLICANTS Mamoru Nakasugi, Kanagawa, JAPAN; Nobuharu Noji, Kanagawa, JAPAN; Tetsu Satake, Kanagawa, JAPAN; Masahiro Matakayama, Kanagawa, JAPAN; Toshihumi Kimba, Kanagawa, JAPAN; Hiroshi Sobutawa, Kanagawa, JAPAN; Shoji Yoshikawa, Tokyo, JAPAN; Takeshi Murakami, Tokyo, JAPAN; Kenji Watanabe, Kanagawa, JAPAN; Tsutomu Kariwato, Kanagawa, JAPAN; Shin Oowada, Kanagawa, JAPAN; Mutsumi Saito, Kanagawa, JAPAN; Yutshiro Yamazaki, Tokyo, JAPAN; Takamitsu Negai, Kanagawa, JAPAN; Ichiro Nagahama, Kanagawa, JAPAN;				
* CONTINUING DATA none				
* FOREIGN APPLICATIONS <ul style="list-style-type: none"> JAPAN 2000-183104 08/27/2000 JAPAN 2000-228101 07/28/2000 JAPAN 2000-335934 11/02/2000 JAPAN 2001-11218 01/18/2001 JAPAN 2001-31901 02/08/2001 JAPAN 2001-31808 02/08/2001 JAPAN 2001-33599 02/09/2001 JAPAN 2001-35089 02/13/2001 JAPAN 2001-158862 05/28/2001 JAPAN 2001-182041 05/30/2001 JAPAN 2001-189304 08/22/2001 				
IF REQUIRED, FOREIGN FILING LICENSE GRANTED 08/28/2001				
Foreign Priority claimed <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No 35 USC 119 (a)-(d) conditions <input type="checkbox"/> Yes <input type="checkbox"/> No <input type="checkbox"/> Minor Filed and Acknowledged Address 23850	STATE OR COUNTRY JAPAN	SHEETS DRAWING 50	TOTAL CLAIMS 60	INDEPENDENT CLAIMS 13
TITLE Inspection system by charged particle beam and method of manufacturing devices using the system				

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